

Notice of References Cited	Application/Control No. 09/903,670	Applicant(s)/Patent Under Reexamination CHIU, CHUI-KUEI	
	Examiner Madeleine AV Nguyen	Art Unit 2625	Page 1 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,073,712 A	12-1991	Hellstrom, Ake A.	250/252.1
*	B	US-5,471,208 A	11-1995	Sauer, Donald J.	341/120
*	C	US-5,617,401 A	04-1997	Hurst, Jr., Jerry E.	369/47.52
*	D	US-6,049,762 A	04-2000	Ganz et al.	702/104
*	E	US-6,164,750 A	12-2000	Subirada et al.	347/19
*	F	US-6,285,799 B1	09-2001	Dance et al.	382/261
*	G	US-6,441,923 B1	08-2002	Balasubramanian et al.	358/3.23
*	H	US-6,822,766	11-2004	Hill et al.	358/474
*	I	US-6,474,767 B1	11-2002	Teshigawara et al.	347/19
*	J	US-2003/0016263 A1	01-2003	TAKAHASHI et al.	347/19
*	K	US-2003/0011828 A1	01-2003	Chiu, Chui-Kuei	358/504
*	L	US-6,683,981 B1	01-2004	Matama, Toru	382/167
*	M	US-6,978,215 B2	12-2005	Nikitin, Arkady	702/95

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 09/903,670	Applicant(s)/Patent Under Reexamination CHIU, CHUI-KUEI	
	Examiner Madeleine AV Nguyen	Art Unit 2625	Page 2 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,394,250 A	02-1995	Shono, Seita	358/3.03
*	B	US-5,577,136 A	11-1996	Tanioka et al.	382/270
*	C	US-5,649,253 A	07-1997	Cocca, J. David	396/392
*	D	US-5,760,918 A	06-1998	Tanioka et al.	358/445
*	E	US-6,164,745 A	12-2000	Nagoshi et al.	347/15
*	F	US-6,163,342 A	12-2000	Suzuki, Masao	348/364
*	G	US-2001/0010736 A1	08-2001	Kadono, Shinya	382/243
*	H	US-2001/0028749 A1	10-2001	Kimura, Shunichi	382/240
*	I	US-2001/0041018 A1	11-2001	Sonoda, Fumihiko	382/275
*	J	US-2003/0016263 B1	01-2003	TAKAHASHI et al.	347/19
*	K	US-2002/0012476 A1	01-2002	Dillen et al.	382/274
*	L	US-6,768,513 B1	07-2004	Watanabe et al.	348/246
*	M	US-6,956,674 B1	10-2005	Ishikawa, Atsushi	358/3.03

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 09/903,670	Applicant(s)/Patent Under Reexamination CHIU, CHUI-KUEI	
	Examiner Madeleine AV Nguyen	Art Unit 2625	Page 3 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,181,081 A	01-1993	Suhan, John M.	356/394
*	B	US-6,044,179	03-2000	Savakis, Andreas E.	382/270
*	C	US-6,424,751	07-2002	Carney et al.	382/272
*	D	US-5,642,202 A	06-1997	Williams et al.	358/406
*	E	US-5,649,073 A	07-1997	Knox et al.	358/1.9
*	F	US-6,459,821	10-2002	Cullen, John	382/294
*	G	US-6,608,941	08-2003	Suzuki et al.	382/272
*	H	US-2002/0014577 A1	02-2002	Ulrich et al.	250/205
*	I	US-6,535,649 B1	03-2003	Chiu, Chui-Kuei	382/274
*	J	US-6,650,442 B1	11-2003	Chiu, Hui-Hsien	358/474
*	K	US-6,711,285	03-2004	Noguchi, Takafumi	382/162
*	L	US-6,768,513 B2	07-2004	Watanabe et al.	348/246
*	M	US-2002/0180869 A1	12-2002	Callison et al.	348/203

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 09/903,670	Applicant(s)/Patent Under Reexamination CHIU, CHUI-KUEI	
	Examiner Madeleine AV Nguyen	Art Unit 2625	Page 4 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,703,512 A	10-1987	Saka et al.	382/199
*	B	US-5,656,802 A	08-1997	Aoki, Harumi	235/454
*	C	US-5,754,920 A	05-1998	Tanaka et al.	399/49
*	D	US-5,773,809 A	06-1998	Watanabe et al.	235/462.27
*	E	US-5,777,313 A	07-1998	Watanabe et al.	235/462.25
*	F	US-6,094,508 A	07-2000	Acharya et al.	382/199
*	G	US-6,154,573 A	11-2000	Murayama et al.	382/254
*	H	US-6,181,356 B1	01-2001	Ohnishi et al.	347/116
*	I	US-2002/0018944 A1	02-2002	Irving et al.	430/21
*	J	US-2002/0114521 A1	08-2002	Fujii et al.	382/209
*	K	US-2002/0122213 A1	09-2002	Hill et al.	358/474
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.